

An inspection-based compositional approach to the quantitative evaluation of assembly lines

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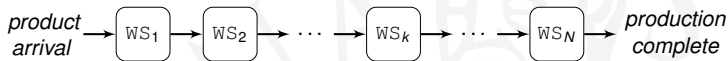
- ▶ Assembly line analysis
 - ▶ for transient measures evaluation
 - ▶ subsequent to an inspection at steady-state
- ▶ subject to ambiguity
 - ▶ on the logical state
 - ▶ and on the remaining times

Analysis of assembly lines

Why analyse assembly lines?

- ▶ Maximize throughput and efficiency
 - ▶ speeding-up/slowing-down workstations in order to balance throughput
 - ▶ identify bottlenecks and focus resources on them
- ▶ Minimize resources and energy consumption
 - ▶ lower power consumption before bottlenecks
- ▶ Adapt production during runtime
 - ▶ Industrie 4.0
 - ▶ e.g. schedule personnel/resources in a tactic perspective

Assembly line

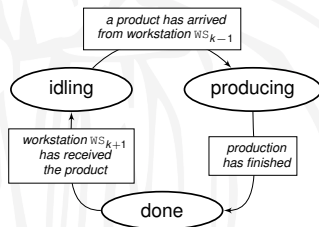


N sequential workstations WS_1, \dots, WS_N

- ▶ with transfer blocking
- ▶ and no buffering capacity

Workstation WS_k can be in one of three states

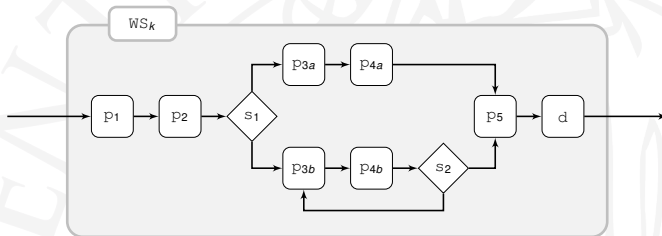
- ▶ *producing*: WS_k is working on a product
- ▶ *done*: WS_k is done working on a product
- ▶ *idling*: WS_k is waiting for a new product



Workstation

Each workstation WS_k

- ▶ has no internal parallelism
 - ▶ at most one item being processed in each workstation
- ▶ can implement complex workflows
 - ▶ sequential/alternative/cyclic phases with random choices
- ▶ and has GEN phases' durations



The last phase has no duration and encodes the *done* state

Underlying stochastic process

The underlying stochastic process of each isolated workstation is a Semi Markov Process (SMP)

- ▶ due to GEN durations
- ▶ and the absence of internal parallelism

The whole assembly line finds a renewal in any case where

- ▶ every *done* station is in a queue before a bottleneck
- ▶ and everything else is *idling*



Inspection with partial observability

The assembly line can be inspected by external observers

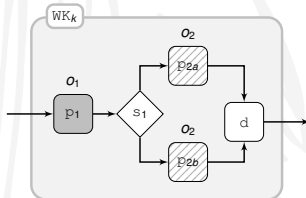
- ▶ the line can be considered at steady-state at inspection
- ▶ there can be ambiguity about the current phase

An observation is a tuple $\omega = \langle \omega_0, \omega_1, \dots, \omega_N \rangle$

- ▶ ω_0 indicates if a new product is ready to enter the line or not
- ▶ $\omega_k = \langle \sigma_k, \phi_k \rangle$ refers to WS_k
 - ▶ σ_k indicates if WS_k is *idle/producing/done*
 - ▶ ϕ_k identifies the set of possible current phases

Two kinds of uncertainty

- ▶ about the actual current phase
 - ▶ discrete
- ▶ about the remaining time in the current phase
 - ▶ continuous



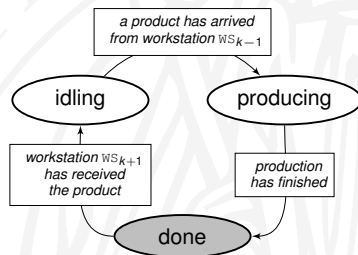
- └ Analysis of assembly lines
- └ Performance measures

Performance measures

Time To Done

Time To Done (TTD)

The remaining time until workstation k ,
according to observation ω , reaches the *done* state



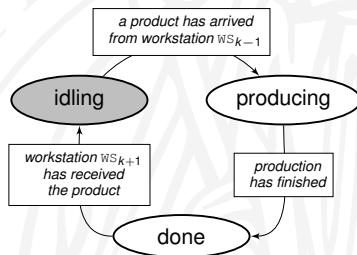
- └ Analysis of assembly lines
- └ Performance measures

Performance measures

Time To Idle

Time To Idle (TTI)

The remaining time until workstation k , according to observation ω , reaches the *idling* state



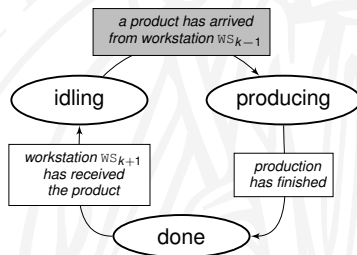
- └ Analysis of assembly lines
- └ Performance measures

Performance measures

Time To Start Next

Time To Start Next (TTSN)

The remaining time until workstation k , according to observation ω , starts the production of a new product

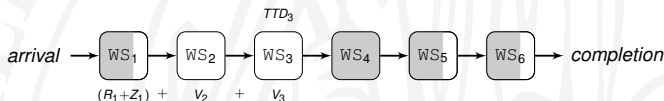


Modelling and solution technique

Time To Done

$$\text{TTD}(k, \omega) := \begin{cases} \sum_{\gamma \in \phi_k} P_{k, \gamma, \omega} \cdot (R(k, \gamma) + Z(k, \gamma)), & \text{if } \sigma_k = \textit{producing} \\ \text{TTD}(k-1, \omega) + V(k), & \text{if } \sigma_k = \textit{idling} \\ 0, & \text{if } \sigma_k = \textit{done} \end{cases}$$

- ▶ $P_{k, \gamma, \omega}$ probability weight that WS_k is in phase γ according to ω
- ▶ $R(k, \gamma)$ remaining time in phase γ of WS_k
- ▶ $Z(k, \gamma)$ execution time of phases of WS_k that follow γ
- ▶ $V(k)$ production time of WS_k

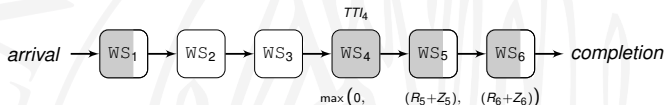


Backward recursive evaluation

Time To Idle

$$TTI(k, \omega) := \begin{cases} \max\{TTD(k, \omega), TTI(k+1, \omega)\}, & \text{if } \sigma_k \in \{\text{producing, done}\} \\ 0, & \text{if } \sigma_k = \text{idling} \end{cases}$$

- ▶ $TTI(k, \omega) = \max\{TTD(k, \omega), \dots, TTD(k+n, \omega)\}$
 - ▶ WS_j producing/done $\forall j \in [k, k+n]$
 - ▶ either WS_{k+n} last workstation or WS_{k+n+1} idling
- ▶ WS_k becomes idle when the bottleneck finishes its production

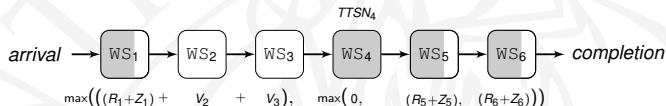


Forward recursive evaluation

- └ Modelling and solution technique
- └ Evaluation of performance measures

Time To Start Next

$$\text{TTSN}(k, \omega) := \max\{\text{TTI}(k, \omega), \text{TTD}(k - 1, \omega)\}$$



Forward and backward recursive evaluation

Disambiguation of observed phases

Resolve observed (producing) phases' ambiguity

- ▶ steady-state probability that WS_k is in phase γ according to ω

Given observation ϕ_k for workstation WS_k

- ▶ we compute probability $P_{k,\gamma,\omega}$
- ▶ that it was actually γ that produced ϕ_k

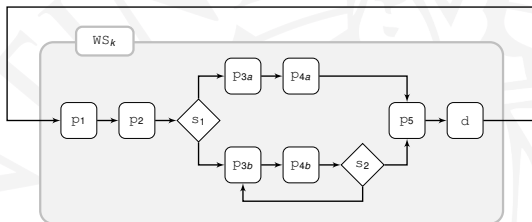
$$P_{k,\gamma,\omega} = \frac{\tilde{\pi}(\gamma)}{\sum_{\gamma' \in \phi_k} \tilde{\pi}(\gamma')}$$

- ▶ $\tilde{\pi}(\gamma)$ steady-state probability of phase γ in an isolated model of WS_k

Isolated workstation model

The isolated workstation model represents a workstation repeatedly processing a product

- ▶ one product being processed
- ▶ after its production, it's moved back to the entry point of the workstation



It can be used for two reasons

- ▶ steady-state probabilities of producing phases are independent
- ▶ the inspection is at steady-state
 - ▶ arrivals and productions can be considered in equilibrium

Remaining time

Evaluation of $F_{R(k,\gamma)}(t)$ = CDF of $R(k, \gamma)$

- ▶ $R(k, \gamma)$ *remaining time* in phase γ of WS_k

Problem!

- ▶ remaining times of enabled GEN transitions are *dependent*
- ▶ joint probabilities don't allow for a compositional approach

1/3 *Immediate* approximation

- ▶ assume that phase γ is inspected at its ending
 - ▶ $\tilde{F}_{R(k,\gamma)}(t) = 1 \quad \forall t$
- ▶ represents an *upper bound*

2/3 *Newly enabled* approximation

- ▶ assume that phase γ is inspected at its beginning
 - ▶ $\tilde{F}_{R(k,\gamma)}(t) = F_\gamma(t)$
 - ▶ $F_\gamma(t)$ original CDF of the duration of γ
- ▶ represents a *lower bound*

Remaining time

$3/3$ Independent remaining times approximation

- ▶ consider the remaining times of ongoing phases as *independent*
- ▶ represents a (better) *lower bound*

Theorem: positive correlation & stochastic order

If \hat{R} is an independent version of vector R of positively correlated remaining times of ongoing phases, then $\hat{R} \geq_{st} R$

Steady-state distribution of $\hat{R}(k, \gamma)$

computed according to the Key Renewal Theorem¹

$$\tilde{F}_{R(k, \gamma)}(t) = \frac{1}{\mu} \int_0^t [1 - F_\gamma(s)] ds$$

- ▶ μ expected value of $F_\gamma(t)$

¹Serfozo, R., 2009. Basics of applied stochastic processes. Springer Science & Business Media.

- └ Modelling and solution technique
- └ Execution and production time

Execution and production time

Evaluation of $F_{Z(k,\gamma)}(t)$ and $F_{V(k)}$

- ▶ $Z(k, \gamma)$ *execution time* of phases of WS_k that follow γ
- ▶ $V(k)$ *production time* of WS_k

CDFs of $Z(k, \gamma)$ and $V(k)$ are computed as transient probabilities

- ▶ $F_{Z(k,\gamma)}$ transient probability from phase after γ to final phase of WS_k
- ▶ $F_{V(k)}$ transient probability from first phase to final phase of WS_k

Upper/lower bounds for TTD , TTI and $TTSN$ can be evaluated

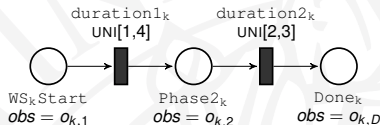
- ▶ *convolution* and *max* operations maintain stochastic order

Experimentation

Experimentation

Models and analyses implemented through the Oris tool²³ APIs

- ▶ modelled through *PO-sTPN*
 - ▶ Partially Observable - stochastic Time Petri Nets
 - ▶ workstations are *state machine PNs* and *1-safe*



Experiments performed on a

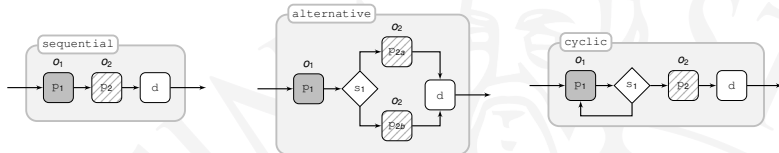
- ▶ single core of an Intel Core i5-6600K processor
- ▶ with 16GB of RAM

²<http://www.oris-tool.org/>

³L. Carnevali, L. Ridi, and E. Vicario, "A Framework for Simulation and Symbolic State Space Analysis of Non-Markovian Models", in International Conference on Computer Safety, Reliability, and Security (SAFECOMP), Lecture Notes in Computer Science, pp. 409-422, Springer Berlin Heidelberg, 2011.

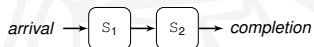
Case study assembly lines

Sequential, alternative and cyclic workstations



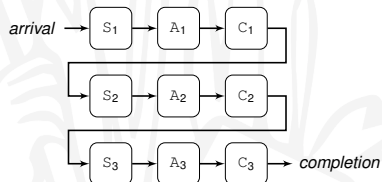
Simple assembly line

- ▶ two sequential workstations
- ▶ both in phase p_1 at inspection



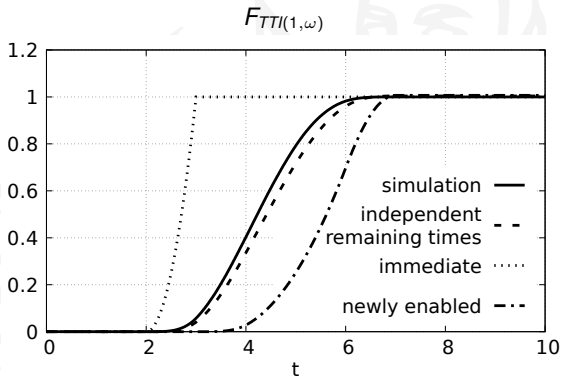
Complex assembly line

- ▶ three repetitions
- ▶ of sequential/alternative/cyclic ws
- ▶ all observed in *producing*



Simple assembly line

$TTIdle$



$TTIdle$ computed in

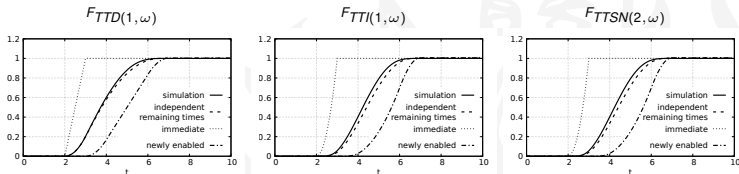
- ▶ 45 min for simulation
- ▶ 0.18 s for bounds

Due to steady-state probabilities

- ▶ steady-state probability of 0.208
- ▶ 79.2% of runs are discarded

Simple assembly line

TTDone, TTIdle, TTStartNext



TTD , TTI and $TTSN$ computed in

- ▶ 41/45/42 min for simulation
- ▶ 0.15/0.18/0.10 s for bounds

Very good approximation results

- ▶ especially for *independent remaining times*

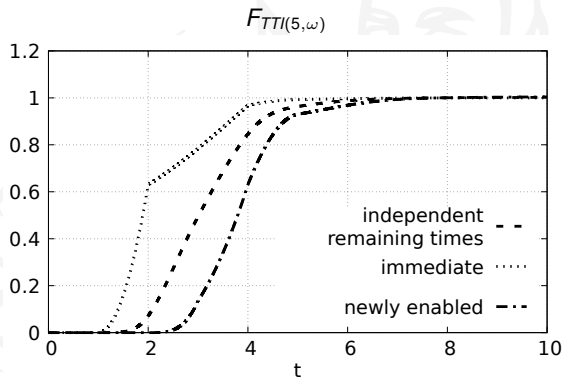
Feasible approach

- ▶ very fast bounds evaluation
- ▶ compared to simulation

- └ Experimentation
- └ Complex assembly line

Complex assembly line

$TTIdle$



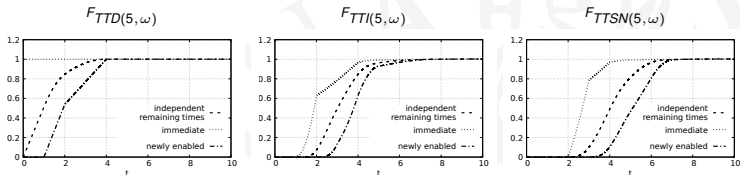
$TTIdle$ computed in

- ▶ 0.123 s for bounds

Simulation would be too computationally expensive

Complex assembly line

$TTDone$, $TTIdle$, $TTStartNext$



TTD , TTI and $TTSN$ computed in

- ▶ 0.126/0.123/0.75 s for bounds

Scalable solution

- ▶ in a complex scenario
- ▶ simulation would be infeasible

Summary

We have proposed a compositional approach

- ▶ for analysis of assembly lines
 - ▶ with transfer blocking and no buffer capacity
- ▶ after inspection
 - ▶ subject to discrete/continuous ambiguity

Leveraging the positive correlation among remaining times

- ▶ we have derived stochastic bounds of performance measures
- ▶ with good and scalable results

Future directions

- ▶ introduce buffer capacity
- ▶ derive additional performance measures
 - ▶ e.g. time to complete the production of a certain product
 - ▶ or of the next N products